

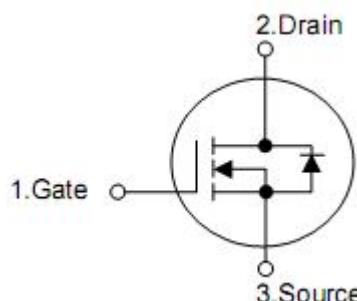
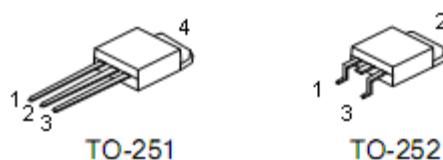
1. Description

This Power MOSFET is produced using KIA advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.

2. Features

- $R_{DS(on)} = 4.3\Omega$ @ $V_{GS} = 10V$
- Low gate charge (typical 6.5nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

4. Absolutemaximum ratings

($T_C=25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DSS}	650	V
Drain current continuous	I_D	2.0	A
$T_C=100^\circ\text{C}$		1.1	A
Drain current pulsed (note1)	I_{DM}	7.5	A
Gate-source voltage	V_{GSS}	± 30	V
Single Pulse avalanche energy (note2)	E_{AS}	100	mJ
Repetitive avalanche energy (note1)	E_{AR}	4.2	mJ
Peak diode recovery dv/dt (note3)	dv/dt	4.5	V/ns
Power dissipation	P_D	42	W
Derate above 25°C		0.33	W/ $^\circ\text{C}$
Operating and storage temperature range	T_J, T_{STG}	-55~+150	$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	T_L	300	$^\circ\text{C}$

5. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	R_{thJC}	3.0	$^\circ\text{C}/\text{W}$
Thermal resistance,case-to-sink typ.	R_{thJS}	50	
Thermal resistance junction-ambient	R_{thJA}	110	

6. Electrical characteristics

($T_J=25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Off characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	650	-	-	V
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}} \Delta T_J$	$I_{\text{D}}=250\mu\text{A}$, Referenced to 25°C	-	0.6	-	$\text{V}/^\circ\text{C}$
Zero gate voltage drain current	I_{DSS}	$V_{\text{DS}}=650\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=520\text{V}, T_C=125^\circ\text{C}$	-	-	10	μA
Gate-body leakage current	I_{GSS}	$V_{\text{GS}}=20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	10	uA
		$V_{\text{GS}}=-20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-10	uA
On characteristics						
Gate threshold voltage	$V_{\text{GS}(\text{TH})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=0.95\text{A}$	-	4.3	5.3	Ω
Dynamic characteristics						
Input capacitance	C_{ISS}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	275	-	pF
Output capacitance	C_{OSS}		-	30	-	pF
Reverse transfer capacitance	C_{RSS}		-	2	-	pF
Switching characteristics						
Turn-on delay time	$t_{\text{D}(\text{ON})}$	$V_{\text{DD}}=325\text{V}, I_{\text{D}}=2.0\text{A}$ $R_G=25\Omega$, (note 4,5)	-	10	-	ns
Rise time	t_R		-	30	-	ns
Turn-off delay time	$t_{\text{D}(\text{OFF})}$		-	40	-	ns
Fall time	t_F		-	40	-	ns
Total gate charge	Q_G	$V_{\text{DS}}=520\text{V}, I_{\text{D}}=2.0\text{A}$ $V_{\text{GS}}=10\text{V}$ (note 4,5)	-	6.5	-	nC
Gate-source charge	Q_{GS}		-	2.2	-	nC
Gate-drain charge	Q_{GD}		-	2.5	-	μC
Drain-source diode characteristics						
Continuous drain-source current	I_S		-	-	2.0	A
Pulsed drain-source current	I_{SM}				7.5	A
Drain-source diode forward voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=2.0\text{A}$	-	-	1.4	V
Reverse recovery time	t_{RR}	$V_{\text{GS}}=0\text{V}, \frac{di_F}{dt}=100\text{A}/\mu\text{s}$ $I_{\text{S}}=2.0\text{A}$,	-	200	-	ns
Reverse recovery charge	Q_{RR}		-	0.75	-	μC

Note: 1. Repetitive rating: pulse width limited by maximum junction temperature

2. $I_{AS}=2.0\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, starting $T_J=25^\circ\text{C}$

3. $I_{SD}\leq 2.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD}\leq \text{BV}_{\text{DSS}}$, starting $T_J=25^\circ\text{C}$

4. Pulse test: pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

7. Test circuits and waveforms

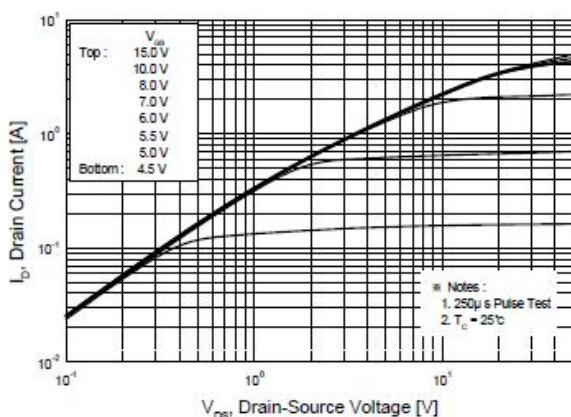


Figure 1. On-Region Characteristics

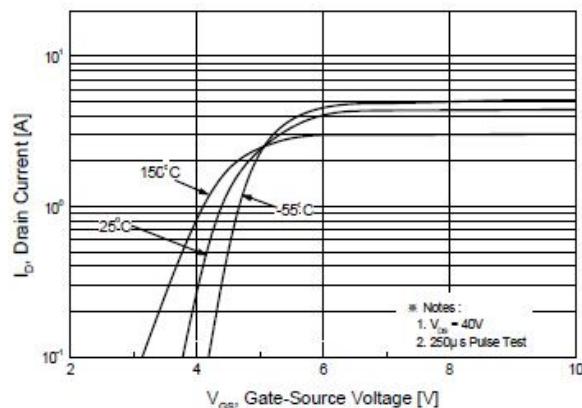


Figure 2. Transfer Characteristics

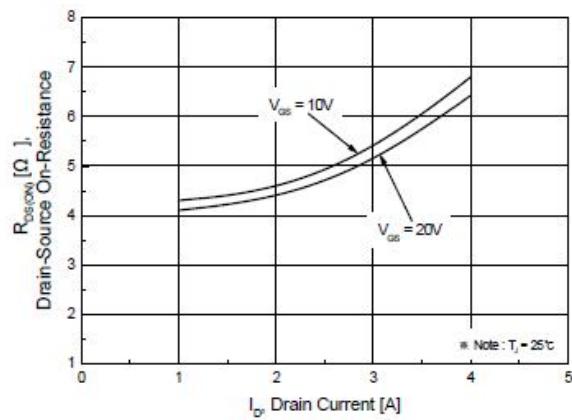


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

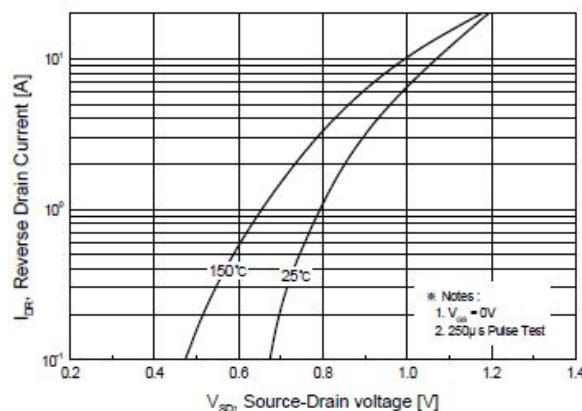


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

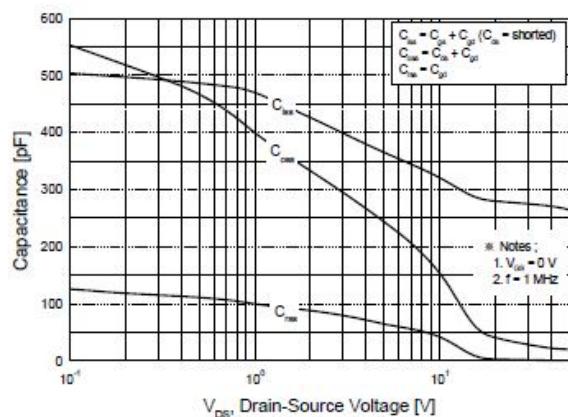


Figure 5. Capacitance Characteristics

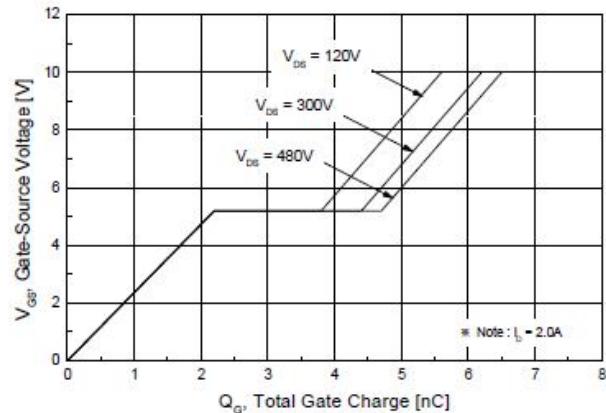


Figure 6. Gate Charge Characteristics

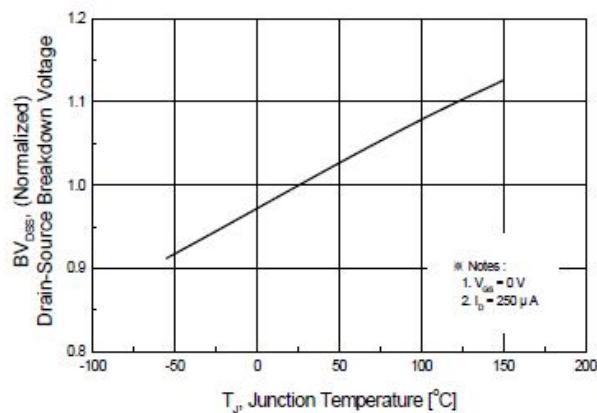


Figure 7. Breakdown Voltage Variation vs Temperature

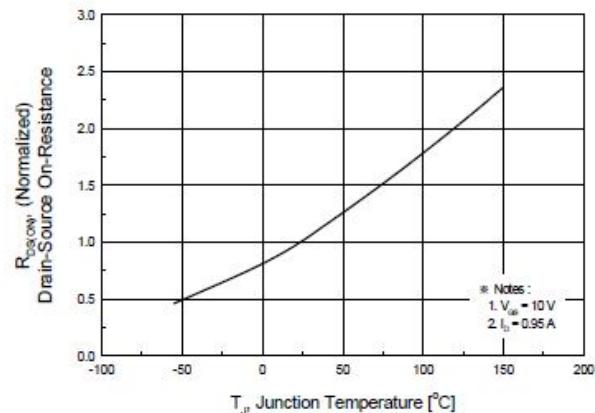


Figure 8. On-Resistance Variation vs Temperature

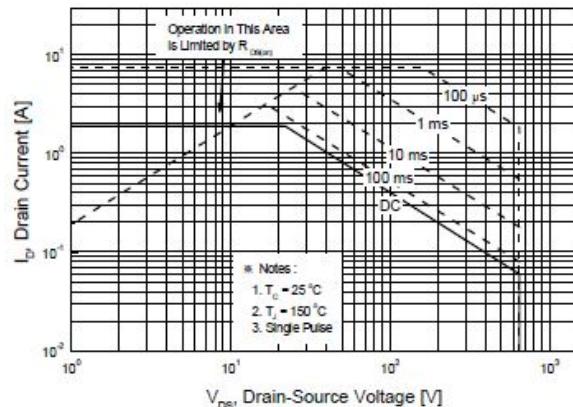


Figure 9. Maximum Safe Operating Area

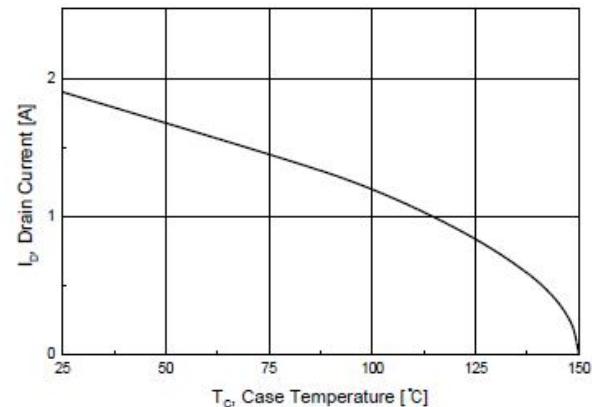


Figure 10. Maximum Drain Current vs Case Temperature

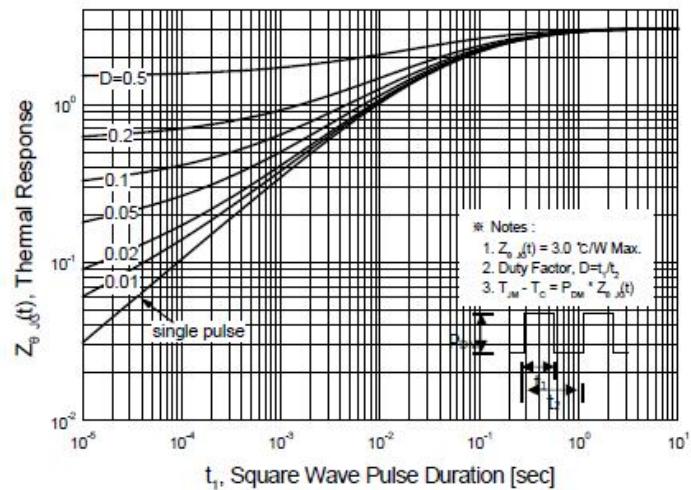


Figure 11. Transient Thermal Response Curve